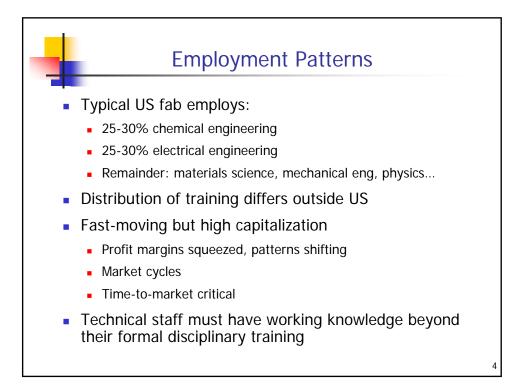
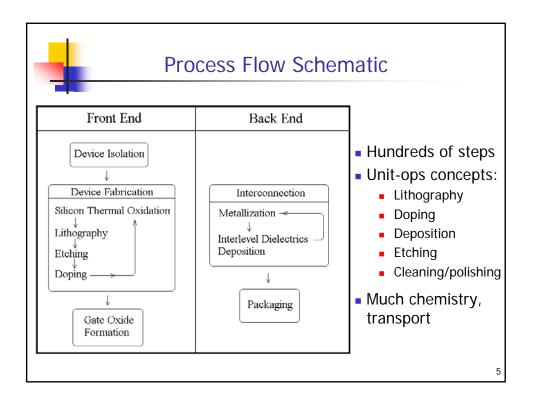
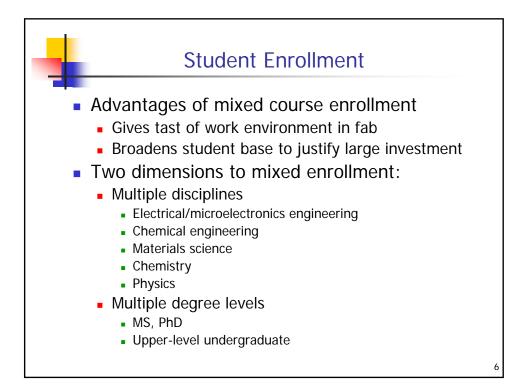
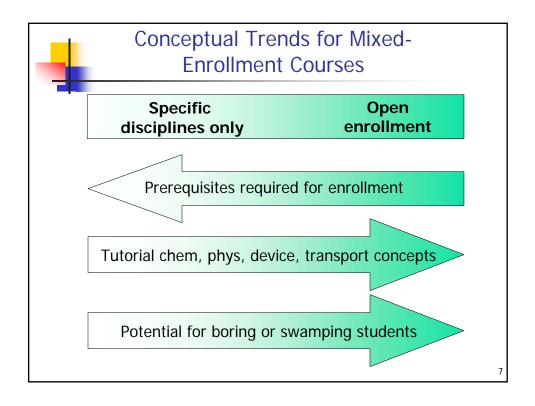


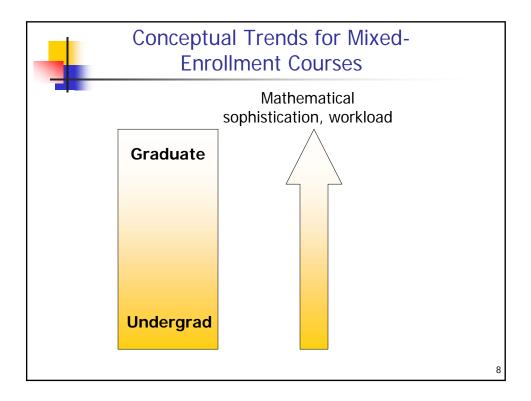
	1999	2001	2004	2007	2010	2013
DRAM half-pitch (nm)	180	130	90	65	45	32
Transistors/chip at production (millions)	61	97	193	386	773	1546
MPU cost/function (μcents/transistor)	120	60	30	15	5.3	1.9

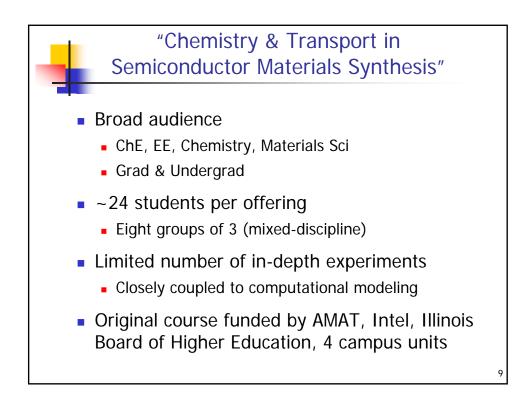


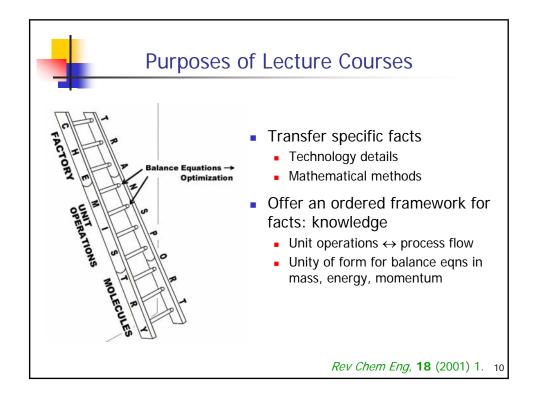


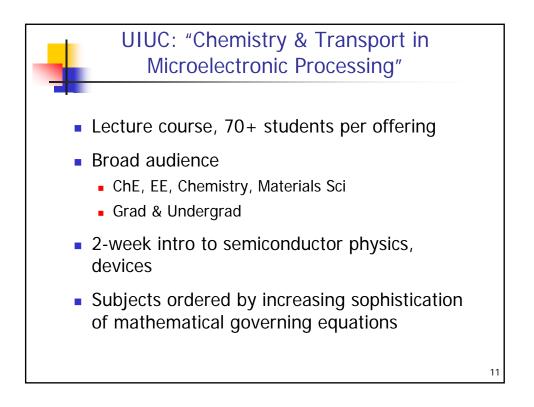


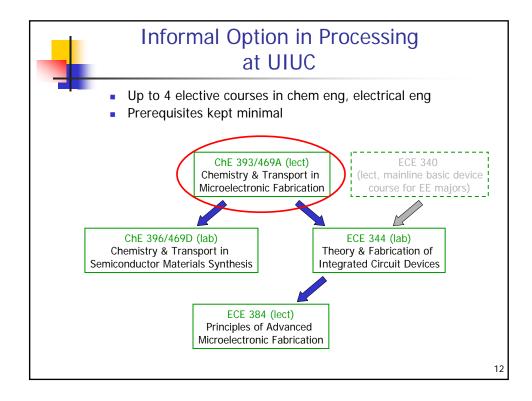


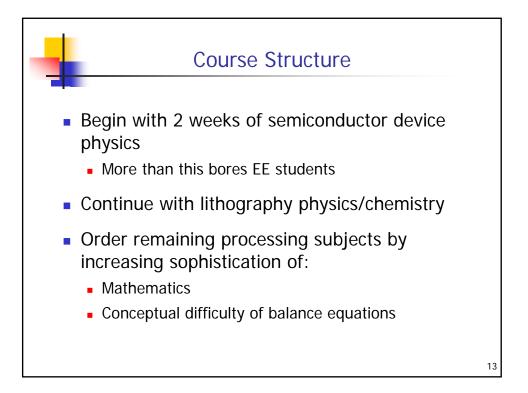


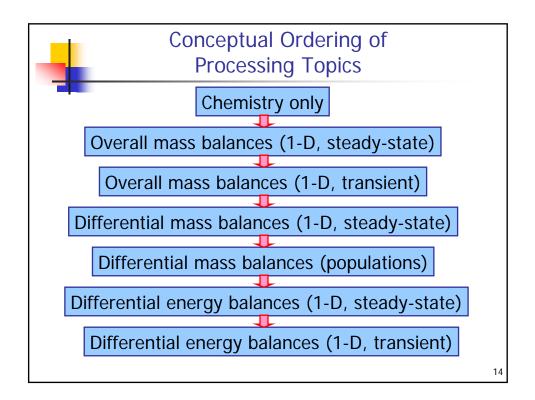












Lect. No.	Topics	Underlying Concepts	
1 2	 Industry history SIA Roadmap Semiconductor materials 	Overall perspective	
3 4 5	 Semiconductor physics pn junctions Field effects 	Solid state physics	
6 7	Lithography	Optics	
8 9	Etching (wet)	Buffers Electrochemistry	

Lect. No.	Topics	Underlying Concept
10	• Etching (dry)	Plasma phenomena
11	• Etching (dry)	Plasma phenomena
12	 Physical vapor deposition 	Sputtering physics Process control
13	Rapid thermal processing	Rate selectivity Process control
	Microelec. Lab Tour	

Lect. No.	Topics	Underlying Concepts
14 15 16 17	Chemical vapor deposition	Surface kinetics Kinetics/gas transport Boundary layers Case study: TiSi ₂
18	Si oxidation	Rate-limiting steps Diffusion-rxn (differential mass balances, 1-D)

Lecturs 19-22			
Lect. No.	Topics	Underlying Concepts	
19 20	Si refining	Well-stirred reactors Differential mass balances on distributions	
21	Czochralski growth	Separations by crystallization Differential energy balances (1-D)	
22	Diffusional doping	Defect thermodynamics Transient diffusion equations	

Lect. No.	Topics	Underlying Concepts	
23	Diffusional doping	Defect thermodynamics Transient diffusion equations	
24	 Ion implantation Transient enhanced diffusion 	Implantation physics Diffusion-rxn (3-D PDE's)	
25	Packaging	Electrochemistry 1-D heat transfer	
26	Factory-level issues	Process integration	

